

**Notice of Allowability**

Application No.

10/050,160

Examiner

JAMES C KERVEROS

Applicant(s)

KITADA ET AL.

Art Unit

2133

-- The MAILING DATE of this communication appears on the cover sheet with the corresponding address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to AMENDMENT filed 10/8/2004.
2. ☒ The allowed claim(s) is/are 1-11.
3. ☒ The drawings filed on 18 October 2002 are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
  - a) ☒ All    b) ☐ Some\*    c) ☐ None    of the:
    1. ☒ Certified copies of the priority documents have been received.
    2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
    3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

\* Certified copies not received: \_\_\_\_\_.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

**THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.**

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
  6. ☐ CORRECTED DRAWINGS ( as "replacement sheets") must be submitted.
    - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review ( PTO-948) attached
      - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date \_\_\_\_\_.
    - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date \_\_\_\_\_.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

**Attachment(s)**

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08),  
Paper No./Mail Date \_\_\_\_\_
4. ☐ Examiner's Comment Regarding Requirement for Deposit  
of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413),  
Paper No./Mail Date \_\_\_\_\_
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other \_\_\_\_\_

*Guy J. Lamarre*  
Primary Examiner

### **DETAILED ACTION**

1. This Office Action is in response to Amendment filed 10/8/2004, in reply to the Office Action mailed June 2, 2004.

#### ***Allowable Subject Matter***

2. Claims 1-11 are allowed.

### **REASONS FOR ALLOWANCE**

3. The following is an examiner's statement of reasons for allowance:

The prior arts of record taken alone or in combination fail to teach, anticipate, suggest or render obvious the claimed invention including the limitations recited in the independent claims, below:

Claims 1 and 3 each recite an apparatus for testing a semiconductor device, including a measuring decision section for "detecting an optimal value of the wait time and measuring, after elapse of the wait time, the electrical characteristics of the semiconductor device on the basis of the response signal outputted from the semiconductor device, making an "OK/NG" decision on the electrical characteristics of the semiconductor device on the basis of the measurement results, if the decision is "NG", remeasuring the electrical characteristics under a newly set wait time, and performing the remeasuring operation on the electrical characteristics until the result of a decision is "OK".

Claims 5 and 11, each recite an apparatus and a method, respectively, for testing a semiconductor device, including a measuring device for setting a test measuring condition and performing the measurement on the semiconductor device under the set

test measuring condition. "A measurement control apparatus for deciding a stable state of the output signal of the semiconductor device, counting the number of measurements, analyzing in real time the measurements and deciding a stable state".

Claims 9 and 10, each recite a method for testing a semiconductor device, including "supplying a test signal to the semiconductor device and, upon receipt of a response signal outputted from the semiconductor device in accordance with the test signal after an elapse of the initialized wait time, and effecting an "OK/NG" decision in accordance with the result of measurement, if the result of the decision is found to be "NG", effecting a repeated setting of the wait time that until the result of the decision is "OK", the wait time is sequentially incremented from the initialized value toward an initially determined maximal value and terminating the setting of the wait time if the result of the decision is "OK".

Consequently, independent claims 1, 3, 5, 9, 10 and 11 are allowed over the prior arts of record. Claims 2, 4 and 6-8 are directly or indirectly depended upon the independent claims and therefore are also allowable.

4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

**Conclusion**

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to JAMES C KERVEROS whose telephone number is (571) 272-3824. The examiner can normally be reached on 9:00 AM TO 5:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert Decady can be reached on (571) 272-3819. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

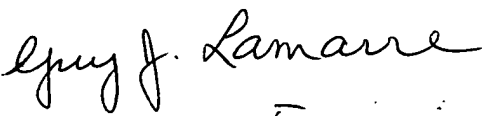
Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

U.S. PATENT OFFICE  
Examiner's Fax: (703) 746-4461  
Email: [james.kerveros@uspto.gov](mailto:james.kerveros@uspto.gov)

Date: 5 January 2005  
Office Action: Allowance

By:  \_\_\_\_\_

JAMES C KERVEROS  
Examiner  
Art Unit 2133

  
Primary Examiner